CVD Diamond Radiation Sensors For Application In Very High Radiation Environments

Seminar presented at University of Geneva

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Peter Weilhammer, for the RD42 Collaboration

CERN Physics Dept. and INFN and University of Perugia, Perugia, Italy RD42 Collaboration: 28 institutes on joined development of CVD diamond detectors

http://rd42.web.cern.ch/rd42/

Industrial Partner: Element Six Ltd H. Murphy, D. Twitchen, A. Whitehead (Element Six, UK)

RD42 Collaboration:

Goal: Development of Diamond as a Detector Material

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Institutes from HEP, Heavy Ion Physics, Hadron Therapy Centers and Solid State Physics

Still growing: new groups joined in 2004 and 2005

Desy-Zeuthen, loffe Institute St. Petersburg, Fachhochschule fuer Technik, Vienna, ITEP Moscow

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IN THIS TALK I WILL PRESENT AN OVERVIEW AND SOME RECENT RESULTS

Content of this presentation:

- 1. INTRODUCTION AND SOME BASIC FACTS ON CVD DIAMOND
- 2. POLYCRYSTALLINE CVD DIAMOND (pCVD)
 - Charge Collection, Results from Irradiations, Applications: the ATLAS Pixel Module, Beam diagnostics and Monitoring with Diamonds
- 3. SINGLE CRYSTAL CVD DIAMONDS (sCVD)
 - Charge Collection, Charge Carrier Properties via TCT

Introduction

Attraction of Semiconductor Sensors for Radiation Detection and for Tracking

For modern detectors in particle physics (and in particular close to the interactions region of colliders) detectors need to ...

Have fast signals and be able to tolerate high rates
High drift velocity and short drift path

Ionization is localized and can achieve very high segmentation

Are free standing with an absolute minimum of "dead" material

 Are relatively radiation hard and easy to operate
 to survive many years of operation without access or replacement: in colliders, in space,....

The central tracking detectors of present and future collider facilities use nearly only semi-conductor detectors (Silicon) Many astrophysics detectors in orbit have silicon trackers: GLAST, AMS,...

Challenge for future detectors: Development of Radiation Detectors for Future Hadron and Linear Colliders which can survive long enough severe radiation environments without bad performance deterioration.

What do we expect:

What are the radiation environments to be expected after initial LHC running: SEVERE!!



Development of ultra-radiation hard semiconductor detectors for the luminosity upgrade of the LHC to 10³⁵ cm-²s-¹ ("Super-LHC").

Challenges:

- Radiation hardness up to 10¹⁶ cm⁻² required
- Fast signal collection (Going from 25ns to 10 ns bunch crossing ?)
- Low mass (reducing multiple scattering close to interaction point)
- **Cost effectiveness** (big surfaces have to be covered with detectors!)

For silicon detectors and other materials (except diamond) this is done in **RD39** and **RD50**.

One way to go: Make Silicon Detectors more radiation-hard :

Main adverse effects in Si after irradiation:

1. <u>Bulk (Crystal) damage</u> due to Non Ionizing Energy Loss ("NIEL"): displacement damage, built up of crystal defects –

- Change of effective doping concentration (higher depletion voltage, under- depletion)
- Increase of leakage current (increase of shot noise, thermal runaway)
- Increase of charge carrier trapping (loss of charge)

2. Surface damage due to Ionizing Energy Loss (IEL)

- accumulation of positive charge in the oxide (SiO2) and the Si/SiO2 interface –

affects: interstrip capacitance (noise factor), breakdown behavior, ...

What happens in physical terms to a silicon detector (equivalently to other semiconductor detectors) which stays for a long time in an high radiation environment:





The leakage current goes up by orders of magnitude with a total fluence of 10¹⁵ cm⁻²



Fig. 2. Collected charge as a function of the 23 GeV proton fluence for standard and oxygenated n-in-p miniature microstrip detectors (source: Ru¹⁰⁶, chip: SCT128A-40 MHz, 800-900 V applied to irradiated devices, measured at -20 °C) [25].

Charge trapping energy levels inside the band gap are created which eat up the electron hole pairs when drifting across the detector before they can be fully collected \rightarrow 70% charge loss at 8 10¹⁵

Remedies for Silicon:

Material engineering

Device engineering

Change of detector operational conditions

Maybe new materials:

4H-SiC, 6H-SiC, GaN, GaAs, CZT, a-Si(H),CVD Diamond

So far lots of progress to improve radiation hardness of Si based sensors

However to get enough charge after irradiation and not to have the signal dominated by noise: quite extreme running conditions required (in Silicon case):

Low temperatures, very high bias voltage,.....

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In this situation it is interesting to study CVD diamond as a detector material; at least for the areas with the highest integrated radiation fluxes

Basic material constants of CVD diamond in comparison

Property	Diamond	4H-SiC	Si	
Band Gap [eV]	5.5	3.3	1.12	
Breakdown field [V/cm]	10^{7}	4×10^{6}	3×10^{5}	
Resistivity [Ω-cm]	$> 10^{11}$	10^{11}	2.3×10^{5}	
Intrinsic Carrier Density [cm ⁻³]	$< 10^{3}$		1.5×10^{10}	
Electron Mobility [cm ² V ⁻¹ s ⁻¹]	1800	800	1350	
Hole Mobility [cm ² V ⁻¹ s ⁻¹]	1200	115	480	
Saturation Velocity [km/s]	228	200	82	
Mass Density $[g \text{ cm}^{-3}]$	3.52	3.21	2.33	
Atomic Charge	6	14/6	IT	New Results on
Dielectric Constant	5.7	9.7	11.9	this
Displacement Energy [eV/atom]	43	25	13-20	
Energy to create e-h pair [eV]	13	8.4	3.6	
Radiation Length [cm]	12.2	8.7	9.4	
Spec. Ionization Loss [MeV/cm]	4.69	4.28	3.21	
Ave. Signal Created/100 μ m [e]	3600	5100	8900	
Ave. Signal Created/0.1% X_0 [e]	4400	4400	8400	

Important Properties of CVD diamond for Tracking:

<u>GOOD</u>

Both electron and hole mobilities are high, signal collection fast At E = 1 V/ μ m high Drift velocities v_d \rightarrow Diamond v_d = 1.67 x 10⁷ cm/sec \rightarrow Silicon v_d = 3.8 0 x 10⁶ cm/sec

Load capacitances of sensor 2.1 times lower than for Si (lower dielectric constant epsilon)

Diamond has 1.3 times less radiation length compared with Si

"Good" CVD Diamond is an insulator (high band gap) with resistivity greater than $10^{14} \Omega$ cm. Leakage current: $I_{leak} \sim 1$ -10 pA/squcm for a 500µm thick sample.

→ Low load capacitances are limiting electronic noise

NOT SO GOOD, but maybe possible to live with

The **generated charge** in diamond is **3600** electron- hole pairs per 100 μm compared with **10600** electron hole pairs in Si. Slightly more favorable when one compares **generated charge per .3% of radiation length (typical silicon sensor thickness)**:

Diamond: ~13900 mean charges in 361 μ m Silicon: ~26800 mean charges in 282 μ m

Lifetime of both holes and electrons is smaller than the transit time at $1V/\mu m$ (in un-irradiated silicon lifetime is 10's of ms): signal loss in bulk by trapping in non-irradiated material





Diamant_DESS8_Seite-gekippt

The Material: single crystals a few micron across at substrate side up to a few 100 μ m across on top of growth side (~500 to 800 µm thick)

Deposited by Chemical Vapor Deposition in Microwave plasma



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Polished growth side

Charge Collection and Radiation Hardness of pCVD Diamond

Principle of detector operation



•Diamond Pixel Detectors for ATLAS and CMS

ATLAS FE/I Pixels (AI)

- Atlas pixel pitch $50\mu m \times 400\mu m$
- Over Metalisation: Al
- ✦ Lead-tin solder bumping at IZM in Berlin

CMS Pixels (Ti-W)



- CMS pixel pitch $125\mu m \times 125\mu m$
- ✦ Metalization: Ti/W
- ✤ Indium bumping at UC Davis
- \rightarrow Bump bonding yield \approx 100 % for both ATLAS and CMS devices

New radiation hard chips produced this year.

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Diodes for ATLAS Beam Conditioning Monitor





Charge Signal versus applied Field

Saturation above 1 V/mm.

Shape governed by mobility $\mu(E)$ dependence.

Metallization typically is a carbide former plus over-metal like Cr/Au Ti/Au Ti/Pt/Au Ti/Pt/Au New better process used recently: Non carbide former Results are very regular



A particular effect is "priming" in pCVD diamonds: When a sample is first biased with a e. g. field of 1 V/micron and with radiation impinging the collected charge will increase with time in average by ~60% after 30 to 60 mins

Recent polycrystalline CVD (pCVD) diamond.

Approaching saturation velocity



Left: Recent pCVD wafer ready for test - Dots are 1 cm apart Right: Collection distance from a dot in the pCVD wafer

Wafers can be grown >12 cm diameter, >2 mm thickness. Collection distance of this wafer 200 μ m (edge) to 310 μ m (center).

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Collection Distance

	-5	-4	-3	-2	-1	0	1	2	3	4	5
5			_	295	283	214	270	255			
4		_	1	279	285	290	259	275	208		
3		276	287	305	252	274	262	275	205	249	
2	272	276	285	294	209	272	277	235	280	226	175
1	262	205	214	282	283	281	280	248	234	266	271
0	255	282	291	278	238	1	253	257	291	291	277
-1	226	262	154	264	213	255	266	276	272	281	286
-2	232	246	265	240	252	255	256	240	266	271	256
-3		261	264	219	187	244	199	227	228	251	
-4			253	239	216	222	210	273	202		
-5				195	125	179	196	117			

Thinning Experiment



Leakage Current in pCVD Diamonds for ATLAS Beam Monitoring System



Leakage currents in 1/10 pA region up to +- 500 V (No guard ring on this devices)

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Leakage current for a very recent pCVD Diamond samples with Guard ring around dot

Positive Polarity



Leakage current for pCVD Diamond samples with Guard ring around dot Negative Polarity

Radiation Hardness Measurements

Summary on Irradiation Studies done over last few years

- Studied with Protons, Neutrons and Pions on pCVD Strip Detectors
- Fluences of 2-3 10¹⁵ particles/cm²
- Generally decrease of leakage current with dose observed.
- Resolution of Strip detectors gets better with fluence.
- 300 MeV Pions damage more than 27 GeV protons.
 - →50% loss of S/N at 2.9 x 10¹⁵ pions/cm².
 →15% loss of S/N at 2.2 x 10¹⁵ protons/cm²
- No loss seen for EM radiation up to 10MGy. (Behnke et al., Nucl.Instrum.Meth. A489 (2002) 230-240.)

Sample CDS-69 had originally ~ 160 μm ccd, 520 μm thick

Proton Irradiation - previously:

Signal to Noise



Data taken over a period of 2 years

- Dark current decreases with fluence
- ♦ 15% loss of S/N at $2.2 \times 10^{15}/{\rm cm}^2$
- \blacklozenge Resolution improves 35% at 2.2 \times $10^{15}/{\rm cm}^2$

Resolution



Irradiation with protons up to ~2 x 10¹⁶!

Sample: $t = 490 \mu m$, ccd = 225 μm

Proton Irradiation - new:



Pulse Height

Left: Pulse height distributions before (blue curve) and after (red curve) the irradiation to $18 \times 10^{15} \text{ p/cm}^2$ (~500Mrad)

Right: Summary of proton irradiation results for pCVD diamond at fixed V

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Results from Irradiations with pions

Landau Distribution before and after irradiation

250 **Signal Distributions from Diamond Tracker CDS-38** entries/2um 00 05 00 00 00 2-strip center of gravity 008entries before irradiation method CDS-38 at 0.6 V/µm $\sigma = 13.7 \,\mu m$ before irradiation mean 66 600 most prob. 44 50 **FWHM 58** 500 after 2.9 E 15 π / cm² 400 £³⁰⁰ 2-strip center of gravity and re-metalization **CDS-38** ₹250 method after 2.9 E 15 π /cm² 300 entries/ mean 28 and re-metalization most prob. 21 200 FWHM 27 σ **= 10.6** μ**m** 100 100 50 E 0 50 100 150 200 250 2-strip transparent signal to single strip noise [] 0 250 0 -100 -80 -60 -40 -20 20 40 60 80 100 0 residual, u_h-u_t [μm]

52% loss of S/N at 2.9 1015 p/cm2

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Spatial Resolution

Residual Distributions in Diamond Tracker

Some Applications

A full ATLAS Pixel Module with pCVD Diamond

Most of this done by the Bonn Pixel group in RD42: M. Mathes, F.Huegging, J. Weingarten, N Wermes and H. Kagan (OSU)

Constructing a full ATLAS Diamond Pixel Module - new:





Various stages of making a module

Very short test in the high energy ATLAS test beam at CERN

Module equipped with 16 fully radhard IBM readout chips





Beam profile All channels are working

The full diamond pixel module at DESY - Hitmap



Analysis in Progress. Hitmap looks good - can easily see scintillator edge.

The full ATLAS diamond pixel module - Noise, Threshold



Results - Noise $\sim 137e$, Mean Threshold 1454e, Threshold Spread $\sim 25e$.

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Excellent correlation with telescope Resolution dominated by multiple scattering. Preliminary residual $\sim 23 \mu$ m - includes contribution from multiple scattering.

Beam Diagnostics and Monitoring with pCVD Diamonds

Beam Diagnostics & Monitoring with Diamonds (ATLAS, CMS, CDF, Belle, BaBar)

- Common Goal: measure interaction rates & background levels in high radiation environment
- Input to background alarm & beam abort
- "DC current"

 Uses beam induced DC current to measure dose rate close to IP
 Benefits from very low intrinsic leakage current of diamond
 Can measure at very high particle rates

 Simple DC (or slow amplification) readout
 Examples:

 BaBar
 - Belle, CDF
 - Similar method planned for CMS

- Single particle counting
 - Counts single particles
 - Benefits from fast diamond signal
 - Allows more sophisticated logic coincidences, timing measurements
 - Used at high particle rates up to
- Requires fast electronics (GHz range)
 with very low noise
- Examples
 - Atlas Beam conditions monitor

ATLAS Beam Conditions Monitor @ LHC

- 4 BCM stations on each side of the Pixel detector
 - Mounted on Pixel support structure at z = +/-183.8 cm and r = 7 cm
 - Each station: 1cm² detector element + Front-end analog readout







Ten ATLAS BCM Modules with double sensor mounting and GHz readout ready for mounting

CVD diamonds and fast amplifiers at ATLAS

- Benefits from very fast signal in diamond
- radiation hard and requires no cooling



Timing of background vs. interactions

• Distinguish collisions from background through time-of-flight measurement Measure number of charged particle/cm2 using analog pulse height



Single Crystal CVD Diamonds

Some first results on charge collection and carrier properties



Recent single crystal CVD (scCVD) diamond.

Pulse height spectrum of various scCVD diamonds (t=210, 320, 435, 685 µm)

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Recent single crystal CVD (scCVD) diamond.



Most Probable charge versus thickness

Charge carrier properties in Single Crystals

- Measure charge carrier properties important for signal formation
 - electrons and holes separately
- Use α-source (Am 241) to inject charge
- Injection
 - Depth about 14µm compared to 470µm sample thickness
 - Use positive or negative drift voltage to measure material parameters for electrons or holes separately
 - Amplify ionization current



The pulse shape of the induced current is recorded (Transient Current Technique)

Ionization current in a sCVD sample

- Drift time and mobility
- Charge Lifetime
- Internal electrical field
- Transit time of charge cloud
 - Signal edges mark start and arrival time of drifting charge cloud
- Two effects determine the shape **during** the drift
 - Charge trapping during drift if any
 - Space charge : decrease of current for holes / increase for electrons with time



$$\begin{split} i_{e,h}(t) &\propto e^{\frac{t}{\tau_{eff_{e,h}}} - \frac{t}{\tau_{e,h}}} \\ \tau_{eff_{e,h}} &= \frac{\epsilon\epsilon_0}{e_0\mu_{e,h}|N_{eff}|} \approx \frac{\epsilon\epsilon_0 t_c V}{e_0 d^2|N_{eff}|} \end{split}$$

time [ns]

The measured drift velocity

• Average drift velocity for electrons and holes

$$v_{dr_{e,h}}(E) = d/t_c$$

• Extract μ_0 and saturation velocity

$$v_{dr} = \frac{\mu_0 E}{1 + \frac{\mu_0 E}{v_s}}$$

- μ_0 for this sample:
 - Electrons: 1714 cm2/Vs
 - Holes: 2064 cm2/Vs
- Saturation velocity:
 - Electrons: 0.96 10⁷ cm/s
 - Holes: 1.41 10⁷ cm/s



The "effective mobility"

• Deduce a calculated mobility from the measured velocity (normally mobility is defined only at low fields with linear relation between field and velocity)



Preliminary carrier lifetime measurements

• Extract carrier lifetimes from measurement of total charge



Charge trapping doesn't seems to limit signal lifetime -> full charge collection (for typical operation voltages and thickness)

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Net effective space charge

» TCT probes the internal field configuration

- Allows precise measurement of space charge if present
- On this sample e.g.
 - Signal decrease due to decreasing electrical field
 - Negative space charge N_{eff} = 2.8 x 10¹¹ cm⁻²



Summary

Further Progress in Charge Collection

300 μm collection distance diamond attained in wafer growth FWHM/MP \sim 0.95 – Working with manufacturers to increase uniformity This diamond process works in production reactors Single Crystal diamonds look quite attractive Have scCVD research contract in operation until 2006

Radiation Hardness of Diamond Trackers

Using trackers allows a correlation between S/N and Resolution With Protons:

Dark current decreases with fluence

 \circ 15% loss of S/N at $2.2 \times 10^{15}/\text{cm}^2$, 25% signal at $20.0 \times 10^{15}/\text{cm}^2$

 \circ Resolution improves 35% at $2.2\times 10^{15}/{\rm cm^2}$

Diamond Pixel Detectors

Successfully constructed a complete ATLAS diamond module

 \circ Bump bonding yield pprox 100 %

Analyzing Module data from DESY

Excellent correlation between telescope and pixel data

Noise, Threshold, Efficiency, Resolution look good

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Beam Conditions Monitoring

Application of diamond successful in BaBar, Belle, CDF Successfully tested ATLAS BCM prototypes • have met all of the ATLAS specs ATLAS diamond BCM system in production (10 modules) ATLAS diamond BCM installation in Fall 05/Winter 2006

First results obtained with single crystal CVD diamonds :

Full charge collection in material up to 1mm thick

Mobility of electrons and holes measured with TCT; very high hole mobility

Carrier lifetimes are bigger than 40 nsec \rightarrow full charge collection

CVD Diamond is very promising material for Radiation Detectors up to fluences where other solid state detectors will no more have required performance using acceptable service and running conditions